



US 20050184696A1

(19) **United States**(12) **Patent Application Publication** (10) **Pub. No.: US 2005/0184696 A1****Anastas et al.**(43) **Pub. Date: Aug. 25, 2005**(54) **HAPTIC PROFILING SYSTEM AND METHOD**(52) **U.S. Cl. 318/567; 345/156; 345/157; 345/161; 345/163; 345/419; 318/568.1**(76) **Inventors: George V. Anastas**, San Carlos, CA (US); **Michael D. Levin**, Los Altos, CA (US); **Danny Grant**, Montreal (CA); **Juan Manuel Cruz-Hernandez**, Montreal (CA); **Pedro Gregorio**, Montreal (CA); **Christophe Ramstein**, San Francisco, CA (US)(57) **ABSTRACT**

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(60) Provisional application No. 60/531,416, filed on Dec. 19, 2003. Provisional application No. 60/551,054, filed on Mar. 9, 2004.

Publication Classification(51) **Int. Cl.⁷ G05B 19/10; G09G 5/00; G09G 5/08; G06T 15/00; G05B 19/18**

An apparatus includes a characterization module configured to receive data associated with operational characteristics of a mechanical device, the operational characteristics being associated with a perceptual experience of the mechanical device. A conversion module is coupled to the characterization module. The conversion module is configured to automatically produce, substantially without user intervention, a parametric data set associated with the mechanical device based on the data. In another embodiment, a method includes receiving data associated with operational characteristics of a mechanical device. The operational characteristics are associated with a perceptual experience of the mechanical device. A parametric data set associated with the mechanical device is produced automatically, without user intervention. The parametric data set is associated with the mechanical device based on the data.

